

List of designations

- 100 schematic block diagram of a setup of a semiconductor production installation
- 101 block of an overall manufacturing process
- 102 block of a first production area
- 103 block of a second production area
- 104 block of a third production area
- 105 block of a fourth production area
- 200 semiconductor chip production installation
- 201 multiplicity of semiconductor chip production sub-installations
- 202 path of a wafer or a lot through the semiconductor chip production installation
- 201 machine
- 301 sensor
- 302 SECS interface
- 303 PDSF file
- 304 log file
- 306 local communication network (LAN)
- 307 memory
- 308 evaluation unit
- 409 limit value of the misalignment value
- 410 wafer exceeding the limit value (FDC defect)
- 411 wafer exceeding the limit value (FDC defect)